EFDS Workshop - Surfaces and Thin Films - Analytics in Practice

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Title	EFDS Workshop - Surfaces and Thin Films - Analytics in Practice
When	Mi, 29. Juni 2016 - Do, 30. Juni 2016

Description

EFDS Workshop - Surfaces and Thin Films - Analytics in Practice

The EFDS in Cooperation with Empa, the Swiss Federal Laboratories for Materials Science and Technology, Dübendorf invites to the Workshop "Surfaces and Thin Films - Analytics in Practice" scheduled on June 29 - 30, 2016 at the Empa Akademie in Dübendorf (near Zürich), Switzerland.

Surfaces and their specifically designed properties are nowadays integral parts of a very wide range of products. Knowing what is at a surface is a prime prerequisite for designing and controlling the functional behavior of such surfaces. Today a broad variety of surface analytical techniques are available, which provide targeted and detailed insights into the chemical and structural properties of surfaces and thin films. They are indispensable tools for the successful development of surface treatments and coatings.

This workshop provides overview of important techniques for surface and thin film characterization.

These are notably:

• Ion beam analysis (RBS, ERDA, NRA)
• XPS (ESCA)
• ToF-SIMS
• Electron microscopy (STEM, SEM)
• Scanning probe microscopies (AFM, STM, MFM)
• XRD and X-ray tomography
• Surface mechanical properties (hardness, modulus)

Date: Wednesday and Thursday, June 29 - 30, 2016
Venue: Empa Akademie, Überlandstraße 129, 8600 Dübendorf (Zürich), Switzerland
Social Evening: Wednesday, June 29, 2016, 18:30 ETH Zürich "Dozentenfoyer"
Program: http://www.efds.org/tl_files/efds/downloads/Veranstaltungen/Workshops/2016/WSEMPA/WSEMPA_2016_2.pdf
Online registration: www.empa-akademie.ch/efds

Venue - Dübendorf (bei Zürich)

Location	Dübendorf (bei Zürich)

City	Dübendorf
Country	CH